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| Notice of References Cited | Application/Control No. 09/975,960 | Applicant(s)/Patent Under Reexamination LAPAILLE ET AL. | |
| | Examiner Matthew W. Genack | Art Unit 2645 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------|----------------|
| | A | US-6,704,546 | 03-2004 | Lucidarme et al. | 455/62 |
| | B | US-5,828,737 | 10-1998 | Sawyer, Francois | 379/114.07 |
| | C | US-6,738,351 | 05-2004 | Qureshi et al. | 370/235 |
| | D | US-6,421,445 | 07-2002 | Jensen et al. | 380/253 |
| | E | US-5,844,940 | 12-1998 | Goodson et al. | 375/222 |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
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| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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